Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/785,294	LEE, YEOU-CHING
Examiner	Art Unit

1732

EDMUND H. LEE

SEARCHED					
Class	Subclass	Date	Examiner		
UPDATED		6/12/2006	EHL		
			<u> </u>		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
264	139,247	6/12/2006	EHL		
	25,274				
	275				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
UPDATED	6/12/2006	EHL	
-			